



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Mitchell, et al.

Serial No.: 10/058,544

Filed: 01/25/02

For: Multiple Contact Vertical Probe Solution Enabling Kelvin Connection

Benefits for Conductive Bump Testing

Docket No.: TI-32531

Examiner: Tang, M

Art Unit: 2829

#3 Election

J. Brunson

6/12/03

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JUN 12 2003

Election

Commissioner of Patents

P.O. Box 1450

Alexandria, VA 22313-1450

MAILING CERTIFICATE UNDER 37 C.F.R. §1.8(A)

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as First Class Mail in an envelope addressed to: Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on June 9, 2003.


Elizabeth Austin

Dear Sir:

The following amendments and remarks are offered in response to the Examiner's Office Action dated 05/07/2003. They are respectfully submitted as a full and complete response to that Action.

The Examiner has required restriction to one of the species as follows:

The species of Figure 3; and
the species of Figure 5.

Election

Applicant elects to prosecute Claims 1-22 directed to the species of Figure 5.

Figure 3 shows that two locations in a probe card include two parallel probe needles. Figure 5 shows that two locations in a probe card include three parallel probe needles. Figure 3 is thus a subset of Figure 5, so Applicant has elected to prosecute the species of Figure 5. Claims 1-22 are not limited to two probes, but instead refer to "at least two" or to "a second" conductive probe. Thus all of claims 1-22 apply to the three probe embodiment of Figure 5, whereas some of those claims may not apply to the two probe embodiment of Figure 3.

Perhaps the Examiner intended a restriction between inventions, in which case the Examiner is invited to call Applicant to discuss such a restriction.

If the Examiner has any questions or other correspondence regarding this application, Applicant requests that the Examiner contact Applicant's attorney at the below listed telephone number and address.

Texas Instruments Incorporated
P.O. Box 655474, M/S 3999
Dallas, TX 75265
Phone: 972 917-5653
Fax: 972 917-4418

Respectfully submitted,



Michael K. Skrehot
Reg. No. 36,682